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P/2699-26

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Toshikazu KITAJIMA et al.

Date : August 27, 2003

Serial No. : 10/624,871

Group Art Unit : ---

Filed : July 21, 2003

Examiner : ---

For : FILM THICKNESS MEASURING METHOD, RELATIVE DIELECTRIC  
CONSTANT MEASURING METHOD, FILM THICKNESS MEASURING  
APPARATUS, AND RELATIVE DIELECTRIC CONSTANT  
MEASURING APPARATUS

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

SUBMISSION

Sir:

Submitted herewith is a copy of art together with a form listing the same for the convenience  
of the Examiner.

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Signature

August 27, 2003

Date of Signature

JAF:lac

Respectfully submitted,

James A. Finder

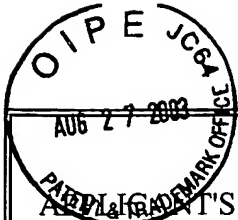
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OSTROLENK, FABER, GERB &amp; SOFFEN, LLP

1180 Avenue of the Americas

New York, New York 10036-8403

Telephone: (212) 382-0700



PRIORITY ART CITATION (Use several sheets if necessary)	Application <b>10/624,871</b>	OFGS File No. <b>P/2699-26</b>
	Applicant <b>Toshikazu KITAJIMA et al.</b>	
	Filing Date <b>July 21, 2003</b>	Group Art Unit <b>--</b>

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
	US-5,475,319	12-1995	Hirae et al.	324	765	
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					

## FOREIGN PATENT DOCUMENTS

	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
	6-349920	12-1994	Japan (corresponds to U.S. Patent No. 5,475,319 listed above)				X

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


Examiner	Date Considered
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